

Controllable Phase Transition Properties in VO₂ Films via Metal-Ion Intercalation

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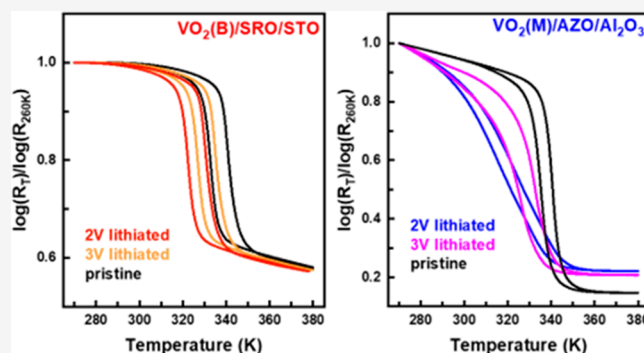
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ABSTRACT: VO₂ has shown great promise for sensors, smart windows, and energy storage devices, because of its drastic semiconductor-to-metal transition (SMT) near 340 K coupled with a structural transition. To push its application toward room-temperature, effective transition temperature (T_c) tuning in VO₂ is desired. In this study, tailorable SMT characteristics in VO₂ films have been achieved by the electrochemical intercalation of foreign ions (e.g., Li ions). By controlling the relative potential with respect to Li/Li⁺ during the intercalation process, T_c of VO₂ can be effectively and systematically tuned in the window from 326.7 to 340.8 K. The effective T_c tuning could be attributed to the observed strain and lattice distortion and the change of the charge carrier density in VO₂ introduced by the intercalation process. This demonstration opens up a new approach in tuning the VO₂ phase transition toward room-temperature device applications and enables future real-time phase change property tuning.

KEYWORDS: VO₂, lithiation, transition temperature tuning, structural deformation, charge carrier density



The semiconductor-to-metal transition (SMT) in oxides has attracted extensive research interest because of significant functional property changes and potential device applications.^{1–5} In particular, vanadium dioxide (VO₂) has been widely studied as a strongly correlated Mott insulator.⁶ VO₂ exhibits an intriguing metal–insulator switching upon cooling near 340 K (67 °C). The ultrafast and reversible first-order phase transition is coupled with a structural transition from rutile to monoclinic upon cooling.^{7,8} In order to push the application of VO₂ toward room temperature, recent efforts have been devoted to the demonstration of transition temperature (T_c) tuning for VO₂ in a broad range. Among all, strain engineering and metallic doping are two common approaches. T_c of VO₂ films can be systemically tailored from 290 to 340 K depending on the lattice-misfit strain^{9,10} and from 308 to 384 K depending on the dopant selection.^{11–14} However, high defect density inevitably deteriorates the overall phase transition properties.^{15,16} Recently, a metal–VO₂ nanocomposite design has been demonstrated to mitigate such degradation.^{17,18} T_c tuning for VO₂ films was achieved by the energy band structure reconstruction at the metal/VO₂ junction. However, most of these T_c tuning methods are based on as-deposited thin films, and demonstrations of postdeposition T_c tuning are limited.

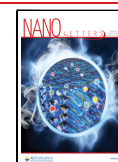
To demonstrate T_c tuning for postdeposition samples, in this study, we adopt the electrochemical intercalation of Li ions as a

novel platform for tailoring the SMT characteristics in VO₂ films. It is interesting to note that VO₂ can be integrated as a cathode material in Li ion batteries due to its unique layered structure.^{19–21} Previous first-principles calculation of Li intercalation in VO₂(B) reveals possible intercalation sites and diffusion paths at different Li concentrations.^{21,22} We thus hypothesize that a controllable SMT characteristic tuning in VO₂ films could be realized by varying the Li concentration during the Li-ion intercalation process. The conceptual schematic of the intercalation process and the proposed mechanism is presented in Figure 1a. During the discharging process, Li ions can intercalate into the VO₂ cathode to form Li_xVO₂. Figure 1b illustrates the electric potential profiles of VO₂(B) with different intercalation strategies, and VO₂(M) shows similar features. ΔV represents the potential difference when the cell is discharged. Therefore, the 3 V lithiated VO₂ film indicates a smaller potential difference than that of the 2 V lithiated VO₂ film. VO₂ is known to have several polymorphs.^{23,24} Specifically, VO₂(B) is selected due to its bilayer

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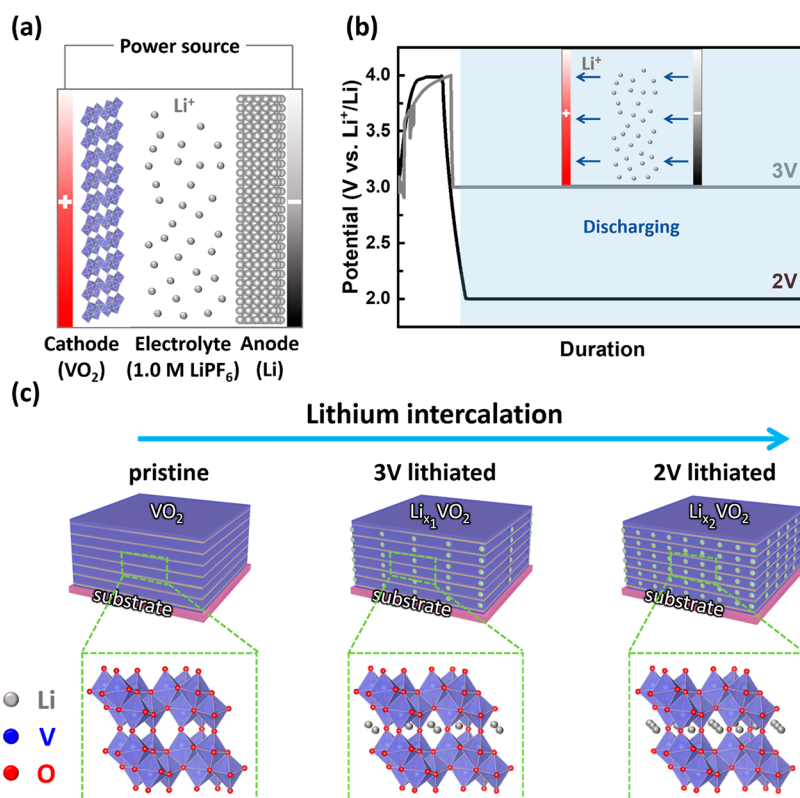


Figure 1. Schematic illustration of the Li-ion intercalation process in VO₂ films. (a) Operating mechanism of the electrochemical intercalation. Li ions are intercalated into the VO₂ cathode during the discharging process. (b) Electric potential profiles of VO₂(B) with different intercalation strategies. ΔV represents the potential difference when the cell is discharged. Therefore, the 3 V lithiated VO₂ film indicates a smaller potential difference as compared to the 2 V lithiated VO₂ film. (c) Proposed intercalation strategy of Li ions in the VO₂ lattice to form Li_xVO₂. The enlarged schematics illustrate the crystal structure of VO₂(B) and the available intercalation sites for Li ions. Because of a smaller potential difference, the 3 V lithiated VO₂ film is supposed to intercalate fewer Li ions as compared to the 2 V lithiated VO₂ film.

structure, which consists of corner-sharing VO₆ octahedra.²⁵ Such a layered structure provides two-dimensional planes for effective diffusion of Li ions during charge/discharge cycling.^{20,21} VO₂(M) is also selected because the distorted VO₆ octahedra share edges to create a similar tunnel structure for Li-ion transport.^{26,27} Compared to the structure of VO₂(B), a denser tunnel in VO₂(M) is supposed to achieve more significant structural deformation and consequently better T_c tuning. A previous structural study during cycling via in situ approaches revealed a reversible change of crystalline structure and oxidation state of V in the cutoff voltage window from 2.0 to 3.6 V.²² Li intercalation in other 2D material candidates (e.g., MoS₂) reveals the significant improvement of electrical conductivity because of carrier injection.²⁸ Here, the microstructural, optical, and electrical characterizations reveal possible mechanisms for T_c tuning upon lithiation. This study provides a promising platform for VO₂-based novel electronics and photonics with potential for real-time electrical and optical property tuning.

In order to investigate the tuning effect of lithiation in VO₂ films by varying Li concentration, the electrical resistivity variation during the phase transition is characterized for the pristine, 3 V, and 2 V lithiated VO₂ films, i.e., VO₂(B) films on SRO-buffered STO substrates and VO₂(M) films on AZO-buffered sapphire substrates. The experimental section is discussed in the [Supporting Information](#). The resistivity of the individual VO₂ layers are calculated by considering VO₂/SRO or VO₂/AZO as parallel resistors. The detailed measurement was reported elsewhere.¹⁰ Figure 2a1,b1 presents the

normalized electrical resistivity, $\rho = \rho(T)/\rho(270 \text{ K})$, of the pristine and lithiated VO₂(B) and VO₂(M) films as a function of temperature. Compared to the resistivity transition curves of the pristine VO₂(B) and VO₂(M) films, the curves of 3 and 2 V lithiated VO₂(B) and VO₂(M) films all shift toward the lower temperature side. Interestingly, the 2 V lithiated VO₂(M) film shows an irregular ρ - T curve. The bump in the curve is likely because of the inhomogeneous phase transition within the VO₂ film: i.e., both metallic and insulating phases coexist in an inhomogeneous transitional state. A similar irregular transition (e.g., more than one endothermic/exothermic peak during the heating/cooling cycle) has been previously reported, which was attributed to the dispersive size distribution of Ti_xV_{1-x}O₂²⁶ or percolated Pt nanoparticles in VO₂ films in previous cases.²⁹ The underlying mechanism will be discussed in detail in a later section. It is possibly due to irregular percolation of switchable metallic domains resulting from partial intercalation within the VO₂ matrix. To study other SMT characteristics (e.g., transition amplitude (ΔA), transition sharpness (ΔT), and the width of thermal hysteresis (ΔH)), the derivation of $\log_{10} \rho$ vs temperature of each sample is calculated based on the resistivity transition curves, as presented in Figure 2a3–5,b3–5. The comparison of T_c and ΔH is summarized in Figure 2a2,b2. Based on the previous VO₂ electrochemical studies, 2 V corresponds to a higher potential difference ΔV and thus a higher Li intercalation amount to Li_{1.0}VO₂. In comparison, 3 V corresponds to a lower potential difference ΔV and thus a lower Li intercalation amount to Li_{0.5}VO₂. Therefore, the electric potential here can

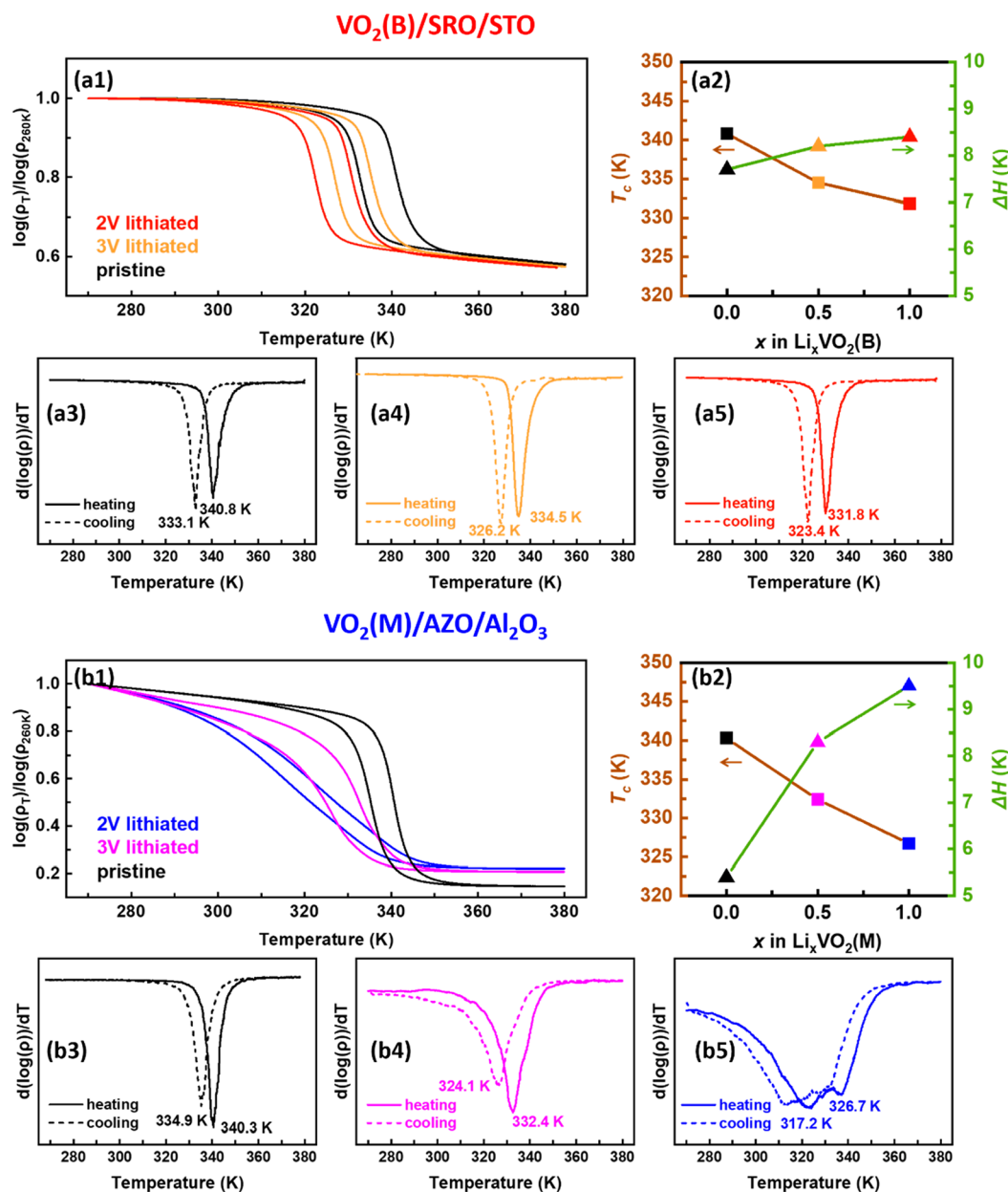


Figure 2. Electrical transport characterization. (a1) Normalized resistivity–temperature curve of the pristine, 3 V, and 2 V lithiated VO₂(B) films on SRO-buffered STO, respectively. (a2) T_c and ΔH trends of VO₂(B) films as a function of electric potential. (a3–a5) Resistivity changing rate of the pristine, 3 V, and 2 V lithiated VO₂(B) films, respectively. (b1) Normalized resistivity–temperature curve of the pristine, 3 V, and 2 V lithiated VO₂(M) films on AZO-buffered c-cut sapphire, respectively. (b2) T_c and ΔH trends of VO₂(M) films as a function of electric potential. (b3–b5) Resistivity changing rate of the pristine, 3 V, and 2 V lithiated VO₂(M) films, respectively.

be correlated to the introduced Li concentration.^{21,30,31} T_c values of both lithiated VO₂(B) and VO₂(M) films are obviously reduced compared to those of their pure VO₂ counterparts, indicating an evident downward T_c tuning with the intercalation of Li ions. Interestingly, T_c of VO₂(M) films shows a more significant decrease than that of VO₂(B). In particular, the lowest T_c is achieved in the 2 V lithiated VO₂(M) film, which is 13.6 K lower than that of the corresponding pure VO₂(M) film.

It is interesting to note that other SMT characteristics (e.g., ΔA , ΔT , and ΔH) exhibit different trends in VO₂(B) and VO₂(M) films. The comparison is summarized in Figure S1 and Table S1. In the case of VO₂(B) films, both ΔA and ΔT prove no distinct degradation after the intercalation, while ΔH

displays a minor increase. The wider thermal hysteresis implies the size reduction of crystalline domains after the Li-ion intercalation.³² On the other hand, in the case of VO₂(M) films, ΔA slightly decreases while ΔT and ΔH obviously increase. The deterioration of the amplitude and the broadening of the transition width are both attributed to the increase of defect content (e.g., point defects, dislocations, grain boundaries, etc.) after the intercalation of Li ions,³³ and the wider thermal hysteresis is related to smaller domains as discussed previously. To summarize, the Li-ion intercalation in both VO₂(B) and VO₂(M) films exhibits evident T_c tuning as well as other SMT characteristics. Such a tuning effect can be further enhanced at higher Li concentration in the VO₂ lattice. In order to understand the underlying mechanisms of T_c

tuning in Figure 2, the microstructural, optical, and electrical transport characterizations are illustrated in the following sections to study the change of strain state and the charge carrier density induced by Li-ion intercalation.

Microstructures of the pristine and lithiated VO₂(B) and VO₂(M) films are systematically characterized using XRD and cross-sectional STEM. Such microstructural characterizations provide essential strain information to probe the structural deformation induced by metal-ion intercalation. All the XRD θ – 2θ spectra in Figure 3a1 show one set of distinct VO₂(B)

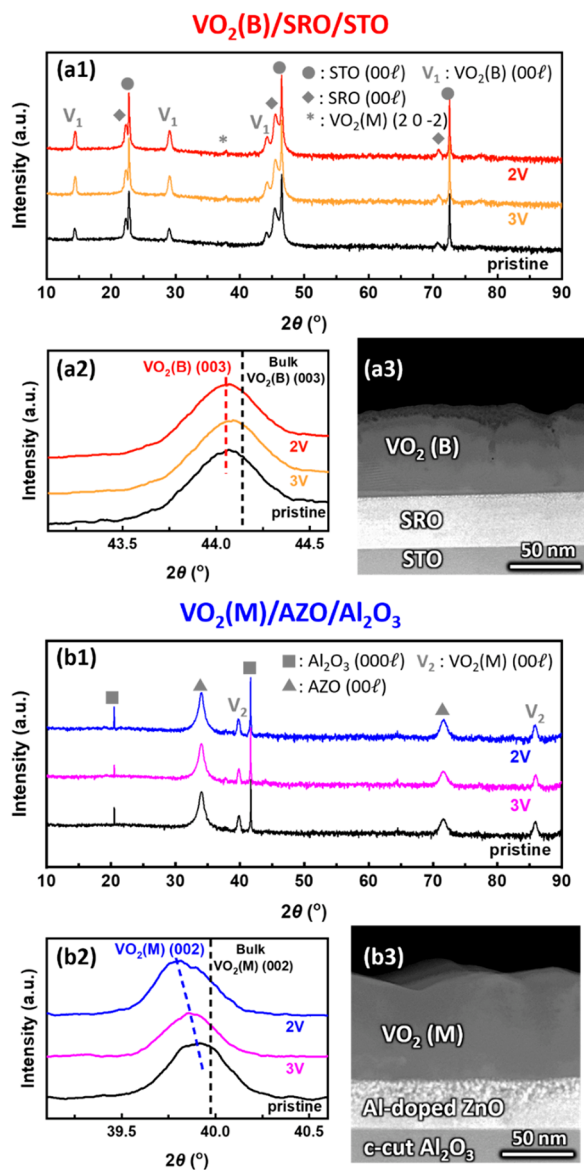


Figure 3. Microstructural characterization. (a1) XRD θ – 2θ spectra of the pristine, 3 V, and 2 V lithiated VO₂(B) films on SRO-buffered STO substrates. (a2) Local scans near the VO₂(B) (003) peak to show the strain within the film. The black dashed line represents the bulk VO₂(B) (003) peak position ($\sim 44.14^\circ$). (a3) Cross-sectional STEM image of the VO₂(B) film on a SRO-buffered STO substrate. (b1) XRD θ – 2θ spectra of the pristine, 3 V, and 2 V lithiated VO₂(M) films on AZO-buffered c-cut sapphire substrates. (a2) Local scans near the VO₂(M) (002) peak to show the strain within the film. The black dashed line represents the bulk VO₂(M) (002) peak position ($\sim 39.97^\circ$). (a3) Cross-sectional STEM image of the VO₂(M) film on an AZO-buffered c-cut sapphire substrate.

peaks corresponding to (00 ℓ), revealing highly textured growth of VO₂(B) films along the c axis on SRO-buffered STO substrates. The existence of a minor peak at around 37.8° is noted, as enlarged in Figure S2. The minor peak marked with an asterisk is considered the VO₂(M) (202) peak, which agrees with a prior study of the textured VO₂(B) growth on a STO substrate, in which a small amount of VO₂(M) can cogrow in the VO₂(B) film when the film thickness exceeds a threshold.³⁴ Figure 3a3 depicts the stack structure of VO₂(B)/SRO/STO. The sharp interface between the VO₂(B) film and SRO buffer is observed without obvious interdiffusion. To explore the change of strain state in VO₂(B) films before and after intercalation, a local XRD θ – 2θ spectra near the VO₂(B) (003) peak is shown in Figure 3a2. There is no obvious shift of VO₂(B) (003) peak before and after intercalation, indicating that limited strain is introduced upon Li ion insertion. Hence, a more localized lattice distortion analysis is required, which will be discussed in more detail in the next section.

On the other hand, in the case of the pristine and lithiated VO₂(M) films, all the XRD θ – 2θ spectra in Figure 3b1 show one set of distinct VO₂(M) peaks corresponding to (00 ℓ), revealing highly textured growth of VO₂(M) films along the c axis on AZO-buffered sapphire substrates. The AZO buffer layer is selected because of its lattice matching relationship with VO₂(M), and the deposition parameters from previous studies are utilized to minimize the interface roughness.¹⁰ The STEM image in Figure 3b3 depicts the stack structure of VO₂(M)/AZO/Al₂O₃. It is noted that the AZO layer has a relatively rough top surface with some columnar features. Such columnar growth of AZO films was reported previously under high oxygen partial pressure,³⁵ and the roughness on the top surface will not have a significant impact on the overall resistivity, as the film is relatively thin and serves as a bottom electrode. Local XRD θ – 2θ spectra near the VO₂(M) (002) peak (Figure 3b2) demonstrate the strain effect in VO₂(M) films before and after intercalation. The peak position of VO₂(M) (002) gradually shifts away from the bulk reference at high Li concentration. The result provides clear evidence of the tensile strain buildup along the c axis upon Li-ion insertion in the VO₂(M) lattice. On the basis of the XRD results, the out-of-plane tensile strains are calculated to be 0.31%, 0.52%, and 0.66% for the pristine, 3 V, and 2 V lithiated VO₂(M) films, respectively.

In order to reveal the local lattice distortion in VO₂(B) films, GPA analysis is conducted on atomic-scale STEM images, as shown in Figure 4. The corresponding in-plane (ϵ_{xx}) and out-of-plane (ϵ_{yy}) lattice strain mappings are presented in Figure 4a2–3, b2–3, c2–3 for the pristine and lithiated VO₂(B) films, respectively. Here, the lower part of the films is selected in each ϵ_{yy} mapping as the reference lattice. No obvious change of ϵ_{xx} is observed upon Li-ion insertion, indicating minimal in-plane lattice distortion. In contrast, the bright yellow contrast in ϵ_{yy} mappings suggests a larger out-of-plane d spacing compared to the reference lattice: i.e., a large out-of-plane lattice expansion in the upper film upon Li-ion insertion. In addition, a sharper change of ϵ_{yy} can be evidently observed at higher Li concentration, indicating the gradual increase in tensile strain along the c axis upon Li-ion insertion in the VO₂(B) lattice. It is also noted that there is a very thin stripe in the top region of Figure 4c2, c3. Such a thin stripe is likely due to the scanning registration error during the STEM imaging process. Interestingly, major strain accumulation is seen within the upper film, suggesting that the Li-ion intercalation occurs

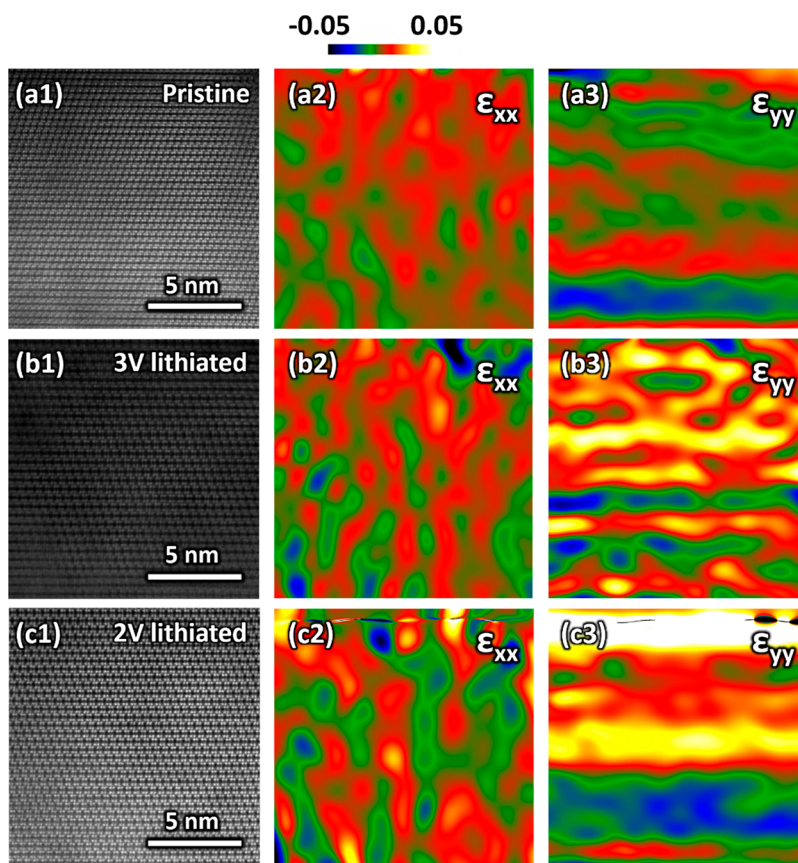


Figure 4. Atomic-scale microstructural characterization of VO₂(B) films on SRO-buffered STO substrates. (a1) Cross-sectional HR-STEM image of the pristine VO₂(B) film. The corresponding geometric phase analysis (GPA) of (a2) in-plane strain (ϵ_{xx}) and (a3) out-of-plane strain (ϵ_{yy}) maps. (b1–b3) Cross-sectional HR-STEM image of the 3 V lithiated VO₂(B) film and the corresponding ϵ_{xx} and ϵ_{yy} maps. (c1–c3) Cross-sectional HR-STEM image of the 2 V lithiated VO₂(B) film and the corresponding ϵ_{xx} and ϵ_{yy} maps.

more obviously in the top layer of the film (~ 18 nm). The intercalation nonuniformity is possibly because of the dense VO₂(B) film. As shown in Figure S3, the TEM comparison of the pristine and the 3 V lithiated VO₂(B) films also confirms the increase of grain boundaries after the intercalation. These observations confirm the existence of a localized structural/phase change and lattice distortion of the VO₂(B) lattice during the intercalation process. Although XRD scans cannot depict an obvious shift of VO₂(B) peaks before and after intercalation, the GPA analysis does illustrate local lattice distortion within the film. The seemingly contradictory results are due to the fact that X-rays penetrate through the entire film thickness and scan a large area, while cross-sectional HRSTEM images focus on a more refined region within the film.

Overall, the microstructural characterization offers essential evidence to investigate the strain accumulation and the localized structural deformation during the metal-ion intercalation process. In particular, VO₂(M) films exhibit obvious tensile strain buildup along the *c*-axis upon Li-ion insertion. In contrast, VO₂(B) films exhibit a more localized lattice distortion upon Li-ion insertion, especially within the upper film. Based on the theoretical calculation, the insertion of Li ions elongates the *c* axis lattice and eliminates the alternating short and long V–V pair separations: i.e., the Li-ion intercalation drives the lattice toward the rutile configuration.³⁶ Thus, the lattice expansion stabilizes the metallic phase and consequently triggers the *T_c* decrease.³⁷ Further, such a structural evolution is reversible in the cutoff voltage window

from 2.0 to 3.6 V.²² As a result, such strain accumulation or structural deformation occurs in both VO₂(M) and VO₂(B) films.

Considering the potential change of charge carrier density induced by Li-ion intercalation, the electrical transport and optical properties of the pristine and lithiated VO₂(B) and VO₂(M) films were systematically characterized using the Van der Pauw method and spectroscopic ellipsometry, respectively. A reliable Hall-effect measurement in VO₂ is challenging considering its low Hall mobility and the inhomogeneous nature of the SMT transition.³⁸ Here, the Hall effect for VO₂(M) films was evaluated in a DC magnetic field of up to 9 T. As shown in Figure S4a–c, the Hall voltage (*V_H*) as a function of magnetic field (*B*) is measured at 380 K to diminish the effect of the AZO buffer layer. For either pristine or lithiated VO₂(M) films, the negative sign of *V_H* implies that electrons are the major carriers to the transport at the metallic phases, which is consistent with prior studies of bulk VO₂.^{38–40} The carrier density $n = -1/(R_H e)$ and the Hall mobility $\mu = R_H/\rho$ are illustrated in Figure S4d, where the Hall coefficient (*R_H*) is determined from the slopes of *V_H* vs *B* curves. It is clear that the charge carrier density almost doubled from $1.23 \times 10^{23} \text{ cm}^{-3}$ (pristine) to $2.27 \times 10^{23} \text{ cm}^{-3}$ (2 V lithiated) when Li ions immigrate through the tunnel structure in the VO₂(M) lattice. The calculated carrier density of the pristine film corresponds to 4.1 itinerant carriers per V ion, which agrees with previous reports of sputtered VO₂.⁴⁰ Although the Hall mobility is reduced slightly at a high Li concentration, the

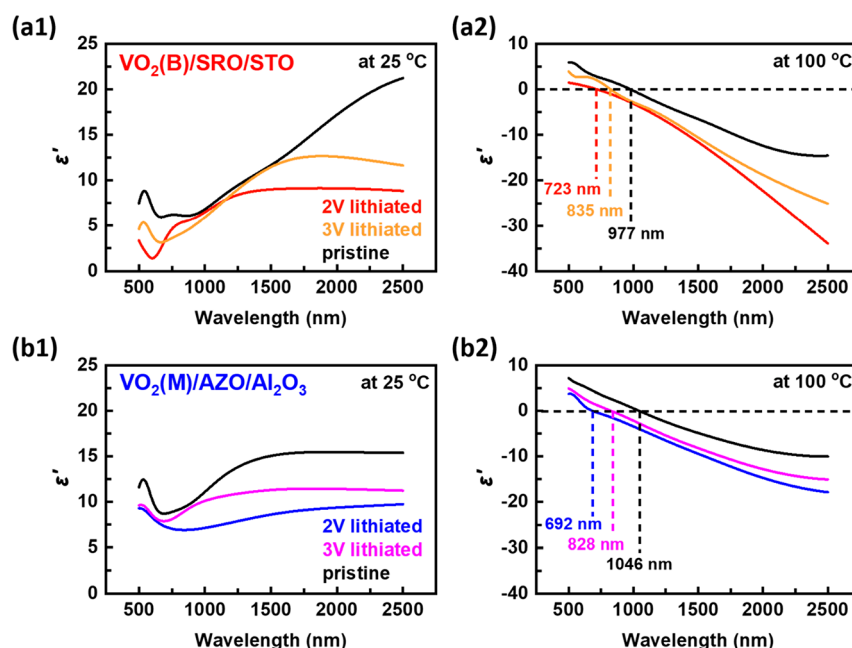


Figure 5. Optical characterization. Dielectric permittivity ϵ' (real part) (a1) at 25 °C and (a2) at 100 °C for the pristine, 3 V, and 2 V lithiated $\text{VO}_2(\text{B})$ films. Dielectric permittivity ϵ' (real part) (b1) at 25 °C and (b2) at 100 °C for the pristine, 3 V, and 2 V lithiated $\text{VO}_2(\text{M})$ films. The inset numbers represent the ENZ wavelengths for the corresponding samples.

overall increase in the number of charge carriers can effectively suppress the SMT transition and consequently trigger the T_c decrease.

The optical absorption in the near-infrared, visible, and ultraviolet regions are closely correlated with the charge carriers in the conduction band.^{41,42} Therefore, the dielectric response of the pristine and lithiated $\text{VO}_2(\text{B})$ and $\text{VO}_2(\text{M})$ films is evaluated using angular-dependent spectroscopic ellipsometry to explore the change of charge carrier density. The dielectric permittivity ϵ' (real part) at 25 °C and at 100 °C is shown in Figure 5 for $\text{VO}_2(\text{B})$ and $\text{VO}_2(\text{M})$ films, respectively. The corresponding ϵ'' (imaginary part) is shown in Figure S5. In both $\text{VO}_2(\text{B})$ and $\text{VO}_2(\text{M})$ films, the values of ϵ' stay positive at 25 °C and become negative at 100 °C. Such an optical response indicates the transition from low-temperature semiconducting behavior to metallic behavior, which is consistent with the electrical resistivity switching in Figure 2. At room temperature, the values of ϵ' decrease with the intercalation of Li ions, indicating the injection of a large amount of charge carriers due to Li-ion diffusion. In particular, $\text{VO}_2(\text{M})$ films exhibit an overall decrease of ϵ' in the UV–vis–NIR region. The dense diffusion tunnel in $\text{VO}_2(\text{M})$ yields a more significant electron doping effect and consequently better optical tuning at RT.⁴³ However, the inferior optical performance of $\text{VO}_2(\text{M})$ film at 100 °C (i.e., smaller ϵ' difference compared to $\text{VO}_2(\text{B})$) is likely due to the inhomogeneous phase transition, as depicted in Figure 4. On the other hand, the tuning effect of Li-ion intercalation at 100 °C is characterized via epsilon-near-zero (ENZ) wavelength. At the metallic phase, a higher Li concentration leads to the shift of ENZ to the high-frequency region. The blue shift of ENZ wavelength reveals the increase of carrier density upon Li-ion insertion, which is consistent with the aforementioned Hall-effect measurement. Overall, the electrical transport and optical characterizations provide essential evidence to reveal the injection of a large amount of charge carriers in $\text{VO}_2(\text{B})$

and $\text{VO}_2(\text{M})$ films during the intercalation process. As previously reported in VO_2 nanobeams, the excess electrons could stabilize the metallic phase at lower temperature by weakening the V–V bonding and reducing the stabilization energy during the structural transformation.^{44,45} Li intercalation in other 2D material candidates (e.g., MoS_2) reveals the significant improvement of electrical conductivity because of carrier injection.²⁸ As a result, the increase of charge carrier density upon Li-ion insertion in both $\text{VO}_2(\text{B})$ and $\text{VO}_2(\text{M})$ effectively suppresses the SMT transition and consequently triggers the T_c decrease.

Compared to other SMT characteristic tuning approaches,^{10,46–49} the electrochemical intercalation of Li ions in this study demonstrates a simple and straightforward approach for effective T_c tuning in a broad range via electric potential control. In the meantime, the metal-ion intercalation approach sustains high-quality VO_2 films with reasonable transition characteristics after the intercalation. Previous studies on Li/Zn/H-ion intercalation in VO_2 and other materials (e.g., MoS_2 , Bi_2Se_3 , graphite, etc.) gives some insights into the possible structural and property changes during the intercalation process.^{28,37,50–52} The evolution of the lattice strain in a Zn/ VO_2 battery during the discharging/charging cycles was indicated by Rietveld refinement,⁵⁰ and the structural defects and strain accumulation in lithiated MoS_2 were characterized by AFM and Raman spectroscopy.²⁸ Both studies revealed the expansion/shrinkage of the lattice (i.e., structural deformation) induced upon proton insertion/extraction. Such structural deformation can suppress the SMT transition and stabilize the metallic rutile phase.³⁷ With respect to other physical properties change, the improved optical transparency and electrical conductivity were observed in Li-ion intercalated MoS_2 ,²⁸ Cu-ion intercalated Bi_2Se_3 ,⁵¹ and Li-ion intercalated graphite,⁵² respectively.

The tunnel structures in both $\text{VO}_2(\text{B})$ and $\text{VO}_2(\text{M})$ can potentially accommodate mass metal-ion intercalation. Taking

advantage of the novel electrochemical platform for Li-ion intercalation, T_c of $\text{VO}_2(\text{B})$ and $\text{VO}_2(\text{M})$ films can be systematically tailored from 326.7 to 340.8 K. The novelty of this work lies in that the Li-ion intercalation approach demonstrates the feasibility of systematic T_c tuning in $\text{VO}_2(\text{B})$ and $\text{VO}_2(\text{M})$ films for the first time. The observed structural deformation and the change of charge carrier density provide possible explanations for T_c tuning and shed insights on VO_2 -based electronics and photonics toward room-temperature applications. While further investigations are under way to quantify the more dominant factor, we argue that the change in carrier density can be more dominant in the case of $\text{VO}_2(\text{B})$. The GPA analysis suggests the existence of localized lattice distortion of $\text{VO}_2(\text{B})$ during the intercalation process, while the obvious peak shift in XRD was not observed. The result indicates limited impact from the global strain state change during the intercalation. Another intriguing future topic is to study the reversibility of Li intercalation, as other 2D material candidates (e.g., MoS_2) exhibit fully reversible discharge/charge cycles with little structural changes on the film edges.²⁸ Other metal-ion candidates, such as Zn ions,^{43,50} Al ions,^{53,54} and Mg ions,^{19,55} that have been previously demonstrated in battery cathode demonstrations can also be explored. Metal-ion intercalation is a powerful method to dynamically engineer the physical properties of VO_2 and other layered materials, which opens up exciting opportunities in integrated electronics and optical devices with real-time property tuning.

In summary, the electrochemical intercalation of Li ions has been demonstrated as a novel platform for T_c tuning in $\text{VO}_2(\text{B})$ and $\text{VO}_2(\text{M})$ films. During the discharging process, Li ions can intercalate into the VO_2 cathode to form Li_xVO_2 . By controlling the relative potential with respect to Li/Li^+ during the intercalation process, T_c of VO_2 is effectively and systematically tailored in the window from 326.7 to 340.8 K. The mechanism of Li-ion induced T_c tuning is mainly attributed to two factors: the structural deformation and the change of charge carrier density. XRD and GPA analysis indicate the strain accumulation in $\text{VO}_2(\text{M})$ films and the lattice distortion in $\text{VO}_2(\text{B})$ films. Hall-effect measurement and spectroscopic ellipsometry reveal the injection of a large amount of charge carriers upon Li-ion insertion. Both factors stabilize the metallic phase and consequently lead to an effective T_c decrease during the intercalation process. The capability to dynamically tailor the phase change properties via an electrochemical intercalation method can be adopted in other layered oxides, which provides a promising approach toward the practical device applications of layered oxides in integrated electronics, optics, and sensors.

■ ASSOCIATED CONTENT

SI Supporting Information

The Supporting Information is available free of charge at <https://pubs.acs.org/doi/10.1021/acs.nanolett.2c03286>.

Additional experimental details, materials, and methods, the comparison of SMT characteristics, XRD, TEM, electrical, and optical properties of the pristine and lithiated $\text{VO}_2(\text{B})$ and $\text{VO}_2(\text{M})$ films (PDF)

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Author Contributions

H.W. conceived and supervised the project. H.W., X.Z., Z.H., and Z.Q. discussed the experimental design and project planning. Z.H. and Z.Q. contributed equally to the thin film fabrication, electrochemical intercalation, and characterization. B.Y. contributed to the electrochemical intercalation. P.L. contributed to the HRSTEM imaging. J.S. contributed to the TEM sample preparation. N.R.D. contributed to the electrical transport measurement. H.W., Z.H., and Z.Q. drafted and revised the manuscript. All authors have revised and given the approval for the final version of the manuscript.

Author Contributions

Z.H. and Z.Q. contributed equally to this work.

Notes

The authors declare no competing financial interest.

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